

November 2013

## FCPF11N60F

# N-Channel SuperFET<sup>®</sup> FRFET<sup>®</sup> MOSFET 600 V, 11 A, 380 m $\Omega$

#### **Features**

- 600 V @ T<sub>J</sub> = 150°C
- Typ.  $R_{DS(on)}$  = 320 m $\Omega$
- Fast Recovery Type (t<sub>rr</sub> = 120 ns)
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 40 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 95 pF)
- · 100% Avalanche Tested
- · RoHS compliant

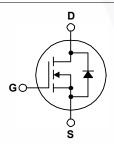
## **Applications**

- LCD/LED/PDP TV
- · Solar Inverter
- Lighting
- · AC-DC Power Supply

## Description

SuperFET® MOSFET is Fairchild Semiconductor's first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low onresistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications. SuperFET FRFET® MOSFET's optimized body diode reverse recovery performance can remove additional component and improve system reliability.





## **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter			FCPF11N60F	Unit
V <sub>DSS</sub>	Drain to Source Voltage			600	V
	Dunin Course	- Continuous ( $T_C = 25^{\circ}C$ )		11*	_
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 100°C)		7*	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	33*	Α
V <sub>GSS</sub>	Gate to Source Voltage			±30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		(Note 2)	340	mJ
AR	Avalanche Current (Note		(Note 1)	11	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		(Note 1)	12.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		(Note 3)	4.5	V/ns
	Dower Dissinction	(T <sub>C</sub> = 25°C)		36	W
P <sub>D</sub>	Power Dissipation - Derate Above 25°C			0.29	W/°C
Γ <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup> Drain current limited by maximum junction termperature.

#### Thermal Characteristics

Symbol	Parameter	FCPF11N60F	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	3.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	°C/W

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCPF11N60F	FCPF11N60F	TO-220F	-	-	50

## Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
D\/	Drain to Source Preakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_C = 25^{\circ}\text{C}$	600	-	-	V
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_C = 150^{\circ}\text{C}$	-	650	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 11 A	-	700	-	V
ı	Zoro Cata Valtaga Prain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	-	-	1	^
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	10	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V	-	-	±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 5.5 \text{ A}$	-	0.32	0.38	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 5.5 A	_	6	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05.V.V 0.V	- \	1148	1490	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz		671	870	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1.0 WHZ	-	63	82	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$	-	35	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	$V_{DS} = 0 \text{ V to } 400 \text{ V}, V_{GS} = 0 \text{ V}$	-	95	-	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 11 A,	-	40	52	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10 V	-	7.2	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4)	-	21	-	nC

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	34	80	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_D = 11 \text{ A},$	/-	98	205	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25 \Omega$	-	119	250	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	56	120	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode	Maximum Continuous Drain to Source Diode Forward Current		-	11	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	33	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 11 A		-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 11 A,	-	120	//-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$V_{GS} = 0 \text{ V, } I_{SD} = 11 \text{ A,}$ $dI_F/dt = 100 \text{ A/}\mu\text{s}$	-	0.8	-	μC

#### Notes

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2. I<sub>AS</sub> = 5.5 A, V<sub>DD</sub> = 50 V, R<sub>G</sub> = 25  $\Omega$ , starting T<sub>J</sub> = 25°C.
- 3.  $I_{SD} \le$  11 A, di/dt  $\le$  200 A/ $\mu$ s,  $V_{DD} \le$  BV $_{DSS}$ , starting  $T_J$  = 25°C.
- 4. Essentially independent of operating temperature.

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

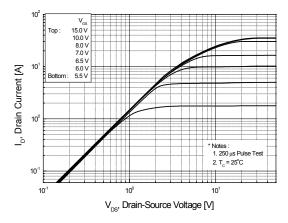


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

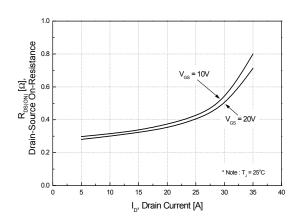


Figure 5. Capacitance Characteristics

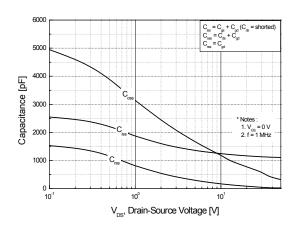


Figure 2. Transfer Characteristics

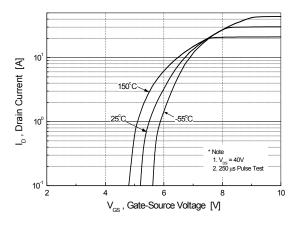


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

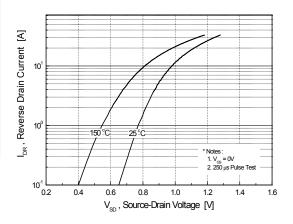
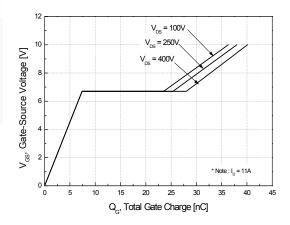


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

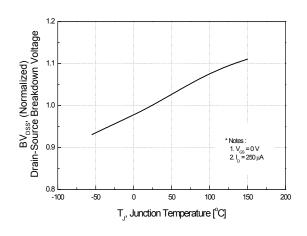


Figure 8. On-Resistance Variation vs. Temperature

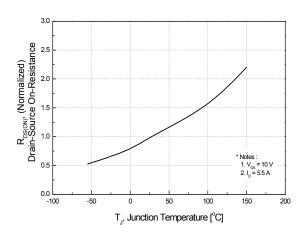
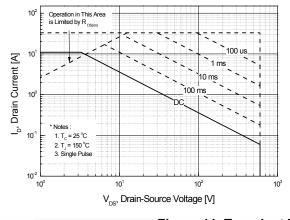


Figure 9. Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature



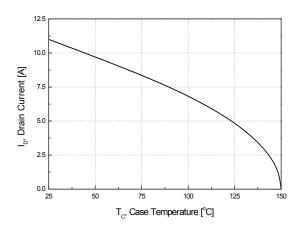
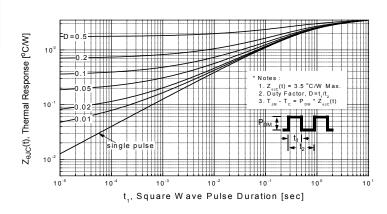


Figure 11. Transient Thermal Response Curve



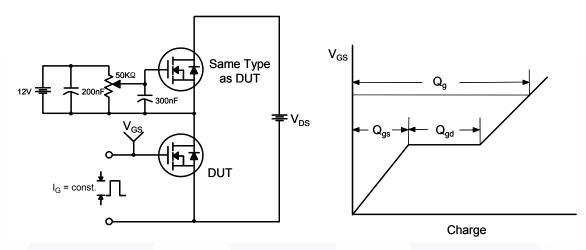


Figure 12. Gate Charge Test Circuit & Waveform

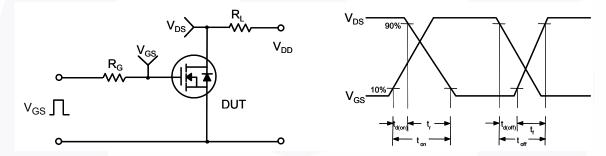


Figure 13. Resistive Switching Test Circuit & Waveforms

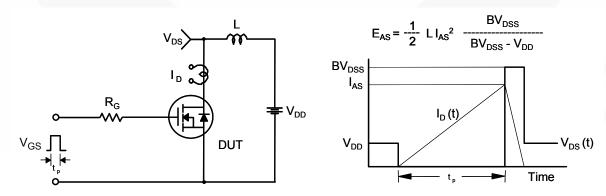


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

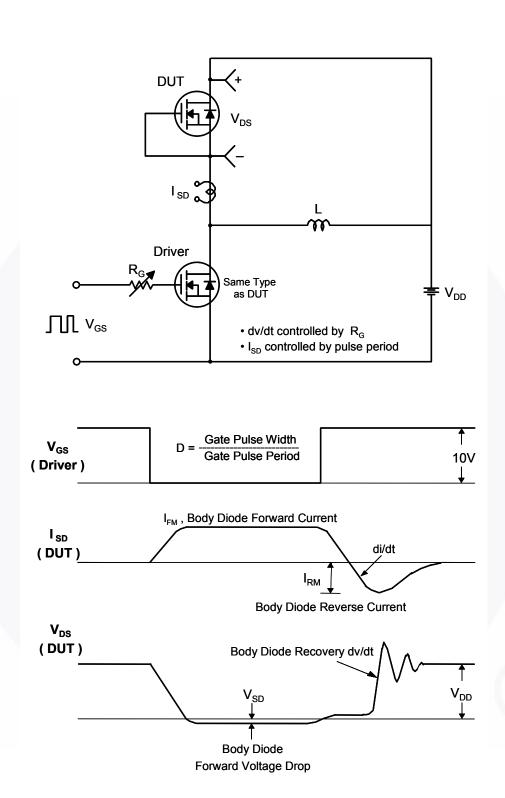


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

## **Mechanical Dimensions**

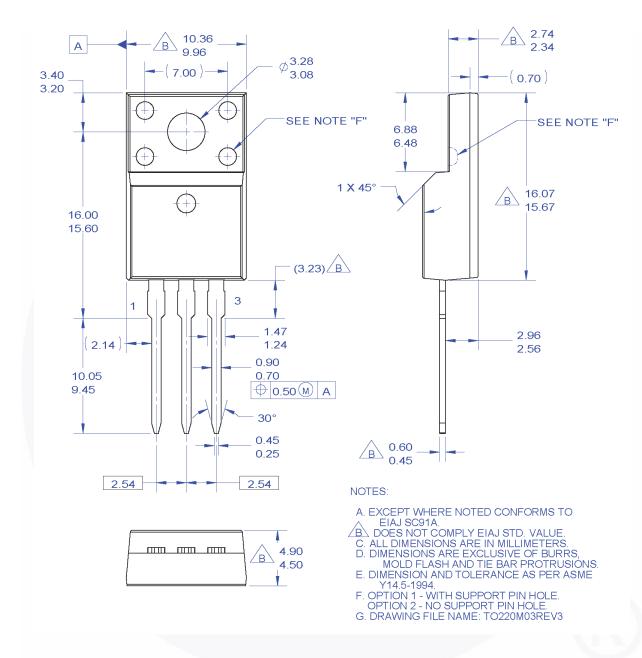


Figure 16. TO220, Molded, 3-Lead, Full Pack, EIAJ SC91, Straight Lead

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